D2684, DECEMBER 1982-REVISED SEPTEMBER 1987

- Multiplexed I/O Ports Provide Improved Bit Density
- Four Modes of Operation: Hold (Store), Shift Right, Shift Left, and Load Data
- High Current 3-State Outputs Drive Bus Lines Directly or Up to 15 LSTTL Loads
- Can Be Cascaded for N-Bit Word Lengths
- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs
- Dependable Texas Instruments Quality and Reliability

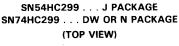
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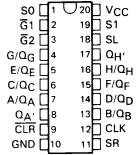
These eight-bit universal registers feature multiplexed I/O ports to achieve full eight-bit handling in a single 20-pin package. 'HC299 applications are as stacked or push-down registers, buffer storage, and accumulator registers.

Two function-select inputs and two output control inputs can be used to choose the modes of operation listed in the function table.

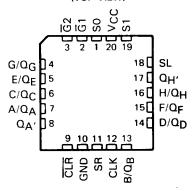
Synchronous parallel loading is accomplished by taking both function-select lines, SO and S1, high. This places the three-state outputs in a high-impedance state, which permits data that is applied on the I/O ports to be clocked into the register. Reading out of this register can be accomplished while the outputs are enabled in any mode. A direct overriding input is provided to clear the register whether the outputs are enabled or off. Taking either of the output controls, $\overline{G}1$ or $\overline{G}2$, high disables the outputs but does not affect the shifting or storage of data.

The SN54HC299 is characterized for operation over the full military temperature range of $-55\,^{\circ}\text{C}$ to 125 $\,^{\circ}\text{C}$. The SN74HC299 is characterized for operation from $-40\,^{\circ}\text{C}$ to 85 $\,^{\circ}\text{C}$.

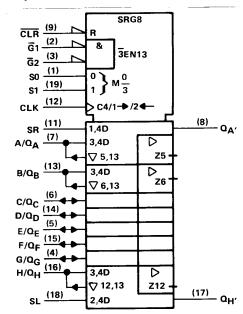




SN54HC299 . . . FK PACKAGE (TOP VIEW)

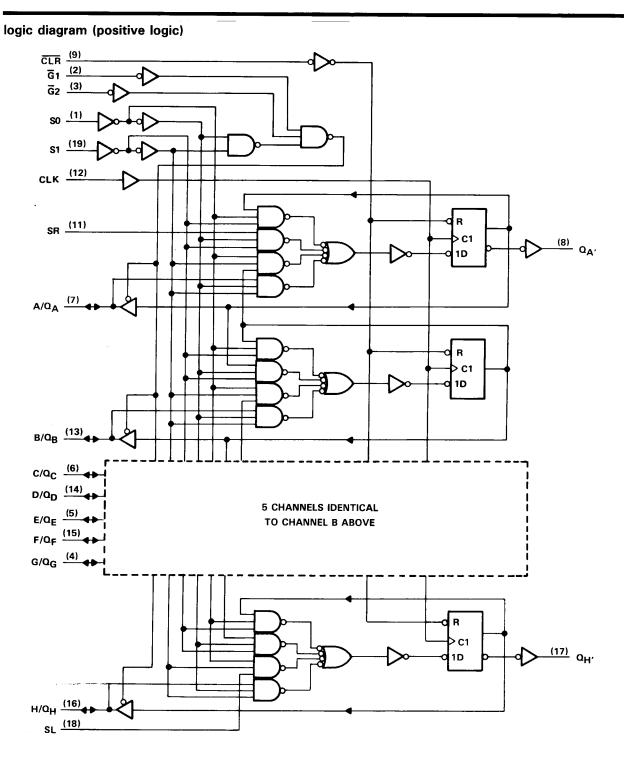


logic symbol†



 $^{\dagger}\text{This}$ symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.







FUNCTION TABLE

		INPUTS						INPUTS/OUTPUTS								OUTPUTS		
MODE	CLEAR	FUNC SEL	TION ECT		TPUT TROL	CLOCK	SEF	RIAL	A/Q _A	B/QB	c/QC	D/QD	E/QE	F/Q _F	G/QG	н/Он	Q _A ,	ŒΗ,
		S1	S0	G 1 [†]	<u>G</u> 2†		SL	SR]									
	L	Х	L	L	٦	Х	Х	Х	L	L	L	L	L	L	L	L	L	L
Clear	L	L	x	L	L	Х	Х	Х	L	L	L	L	L	L	L	L	L	L
	L	Н	н	Х	Х	Х	х	Х	Х	Х	Χ	Χ	Х	X	X	X	L	L
Hold	Н	L	L	L	L	Х	Х	Х	Q _A O	σBO	σco	σDO	σEO	QFO	α_{G0}	σH0	QAO	a H0
Hold	н	X	X	L	L	L	Х	Х	Q_{AO}	σ^{B0}	σ_{CO}	σ_{D0}	σ^{EO}	Q_{FO}	a_{G0}	σ^{HO}	QAO	σ_{HO}
Shift Right	Н	L	Н	L	L	1	Х	Н	Н	Q _{An}	α _{Bn}	Q _{Cn}	Q _{Dn}	QEn	QFn	QGn	H	QGn
Shirt night	н	L	н	L	L	1	Х	L	L	q_{An}	a_{Bn}	a_{Cn}	σ_{Dn}	α_{En}	Q_{Fn}	Q_{Gn}	L	Q_{Gn}
Chife I ofe	Н	Н	L	L	L	1	Н	Х	Q _{Bn}	Ω _{Cn}	Ω _{Dn}	Œη	Ω _{Fn}	QGn	Q _{Hn}	Н	Q _{Bn}	Н
Shift Left	н	Н	L	L	L	1	L	Х	α_{Bn}	a_{Cn}	Q_{Dn}	σ_{En}	Q_{Fn}	α_{Gn}	σ_{Hn}	L	Q _{Bn}	L
Load	Н	Н	Н	Х	Х	1	Х	Х	а	b	С	d	е	f	g	h	а	h

[†]When one or both output controls are high the eight input/output terminals are disabled to the high-impedance state; however, sequential operation or clearing of the register is not affected.

absolute maximum ratings over operating free-air temperature range †

Supply voltage, VCC	-0.5 V to 7 V
Input clamp current, IJK ($V_I < 0$ or $V_I > V_{CC}$)	± 20 mA
Output clamp current, IOK ($VO < 0$ or $VO > VCC$)	± 20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	± 35 mA
Continuous current through VCC or GND pins	± 70 mA
Lead temperature 1,6 mm (1/16 in) from case for 60 s: FK or J package	300°C
Lead temperature 1,6 mm (1/16 in) from case for 10 s: DW or N package	260°C
Storage temperature range	35°C to 150°C

[†]Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

			SN54HC299		SN74HC299			UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
Vcc	Supply voltage		2	5	6	2	5	6	V
		V _{CC} = 2 V	1.5			1.5			
V_{IH}	High-level input voltage	$V_{CC} = 4.5 \text{ V}$	3.15			3.15			\ \ \
		V _{CC} = 6 V	4.2			4.2			
	-	V _{CC} = 2 V	0		0.3	0		0.3	
V_{IL}	Low-level input voltage	$V_{CC} = 4.5 V$	0		0.9	0		0.9	V
	Succession of grades (AMMONIA Adaption)	V _{CC} = 6 V	0		1.2	0		1.2	l
٧١	Input voltage		0		Vcc	0		Vcc	٧
۷o	Output voltage		0		Vcc	0		Vcc	V
-		V _{CC} = 2 V	0		1000	0		1000	
tt	Input transition (rise and fall) times	$V_{CC} = 4.5 V$	0		500	0		500	ns
		$V_{CC} = 6 V$	0		400	0		400	
TA	Operating free-air temperature		- 55		125	- 40		85	°C

a . . . h = the level of the steady-state input at inputs through H, respectively. These data are loaded into the flip-flops while the flip-flop outputs are isolated from the input/output terminals.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	TEAT COMPLETIONS	W	T,	A = 25	°C	SN54	1C299	SN74H	1C299	UNIT
PARAMETER	TEST CONDITIONS	vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	ONT
		2 V	1.9	1.998		1.9		1.9		
	$V_I = V_{fH}$ or V_{IL} , $I_{OH} = -20 \mu A$	4.5 V	4.4	4.499		4.4		4.4		
		6 V	5.9	5.999		5.9		5.9		
VOH	$V_I = V_{IH} Q_{A'}$ and $Q_{H'} I_{OH} = -4 \text{ mA}$ or $V_{IL} A/Q_n$ thru $H/Q_n I_{OH} = -6 \text{ mA}$	4.5 V	3.98	4.30		3.7		3.84		V
	$V_I = V_{IH}$ $Q_{A'}$ and $Q_{H'}$ $I_{OH} = -5.2$ mA or V_{IL} A/Q_n thru H/Q_n $I_{OH} = -7.8$ mA	6 V	5.48	5.80		5.2		5.34		
		2 V		0.002	0.1		0.1		0.1	
	$V_I = V_{IH}$ or V_{IL} , $I_{OL} = 20 \mu A$	4.5 V		0.001	0.1		0.1		0.1	
		6 V		0.001	0.1		0.1		0.1	
VOL	$V_I = V_{IH}$ $Q_{A'}$ and $Q_{H'}$ $I_{OL} = 4 \text{ mA}$ or V_{IL} A/Q_n thru H/Q_n $I_{OL} = 6 \text{ mA}$	4.5 V		0.17	0.26		0.4		0.33	V
	$V_I = V_{IH} Q_{A'}$ and $Q_H Q_{OL} = 5.2 \text{ mA}$ or $V_{IL} A/Q_n$ thru $H/Q_H Q_{OL} = 7.8 \text{ mA}$	6 V		0.15	0.26		0.4		0.33	
I _L	V _I = V _{CC} or 0	6 V		± 0.1	± 100		± 1000		± 1000	nΑ
loz†	$V_O = V_{CC}$ or 0, $V_I = V_{IH}$ or V_{IL}	6 V		±0.01	±0.5		± 10		± 5	μΑ
lcc	$V_I = \forall CC \text{ or } 0, I_O = 0$	6 V			8		160		80	μΑ
C _i ‡		2 to 6 V		3	10		10		10	pF

 $^{^\}dagger For~I/O~ports~(Q_A~through~Q_H)$, the parameter I_J is included in the off-state output current.

timing requirements over recommended operating free-air temperature range (unless otherwise noted)

	-	<u> </u>		T _A =	25°C	SN54	HC299	SN74HC299		UNIT
			Vcc	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
		·	2 V	0	6	0	4.2	0	5	
fclock	Clock frequency	Clock frequency		0	31	0	21	0	25	MHz
	•		6 V	0	36	0	25	0	29	
		2 V 80 120 100								
tw	Pulse duration	CLK high, CLK low,	4.5 V	16		24		20		ns
		or CLR low	6 V	14		20		17		
			2 V	175		263		219		
		S0 or S1	4.5 V	35		53		44		ns
	Setup time		6 V	30		45		37		
		SL or SR	2 V	100		150		125		
t _{su}			4.5 V	20		30		25		ns
00	before CLK1		6 V	17		26		21		
			2 V	65		98		81		
		Data or	4.5 V	13		20		16		ns
	to a management processor of the second	CLR inactive	6 V	11		17		14		
			2 V	0		0		0		
th	Hold time		4.5 V	0		0		0		ns
-11	after CLK↑		6 V	0		0		0		

[‡]This parameter, C_I, does not apply to transceiver I/O ports.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted), $C_L = 50 pF$ (see Note 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V	T	= 25	5°C	SN54	1C299	SN74I	1C299	
TANAMETER	THOM (MEOT)	10 (001701)	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	6			4.2		5		
f _{max}			4.5 V	31			21		25		MHz
			6 V	36			25		29		
			2 V	1	45	170		285		210	
		Q _A , or QH,	4.5 V		16	38		57		48	ns
	CLK		6 V		13	32		48		40	:
^t pd	CLK		2 V		42	170		285		210	
ļ		QA thru QH	4.5 V		16	38		57		48	ns
			6 V		12	32		48		40	
			2 V		60	160		240		200	
ŀ	G1 or G2		4.5 V		24	32		48		40	ns
			6 V	ĺ	23	27		41		34	
^t en		QA thru QH	2 V		115	300		450		375	
	S0 or S1		4.5 V		44	60		90		75	ns
			6 V		39	51		77		64	
			2 V	<u> </u>	60	160		240		200	
	$\overline{G}1$, or $\overline{G}2$		4.5 V		24	32		48		40	ns
	-		6 V		23	27		41		34	
^t dis		Q _A thru Q _H	2 V		115	300		450		375	
	SO or S1		4.5 V		44	60		90		75	ns
			6 V		39	51		77		64	
			2 V		41	210		315		250	
		Q _{A'} or Q _{H'}	4.5 V		17	42		63		53	ns
			6 V		13	36		54		45	
tPHL	CLR	-	2 V		50	200		315		250	
		Q _A thru Q _H	4.5 V		17	42		63		53	ns
		,, ,,	6 v		13	36		54		45	
			2 V		38	75		110		95	
		Q _A , or QH,	4.5 V		8	15		22		19	ns
			6 V		6	13		19		16	
t _t			2 V		38	60		90		75	
		Q _A thru Q _H	4.5 V]	8	12		18		15	ns
		-A	6 V		6	10		15		13	113

C _{pd}	Power dissipation capacitance	No load, T _A = 25 °C	100 pF typ

NOTE 1: Load circuit and voltage waveforms are shown in Section 1.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted), $C_L = 150 \text{ pF (see Note 1)}$

PARAMETER	FROM (INPUT)	то (оитрит)	vcc	$T_A = 2$	5°C	SN54HC299	SN74HC299	UNIT	
TANAMETER		10 (001101)	VCC	MIN TYP	MAX	MIN MAX	MIN MAX	ONIT	
			2 V	56	230	345	288		
^t pd	CLK	Q _A thru Q _H	4.5 V	21	46	69	58	ns	
			6 V	16	39	59	49		
		,	2 V	94	220	330	275		
	$\overline{G}1$ or $\overline{G}2$		4.5 V	38	44	66	55	ns	
. . [Q _A thru Q _H	6 V	33	37	56	47		
t _{en}	S0 or S1		2 V	130	450	675	563		
			4.5 V	59	90	135	113	ns	
			6 V	49	77	115	96		
			2 V	63	260	390	325		
^t PHL	CLR	QA thru QH	4.5 V	21	52	78	65	ns	
			6 V	17	44	66	55		
			2 V	45	210	315	265		
t _t	Q _A thru Q _F	Q _A thru Q _H	4.5 V	17	42	63	53	ns	
			6 V	13	36	53	45		

NOTE 1: Load circuit and voltage waveforms are shown in Section 1.

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